

<b>Notice of References Cited</b>		Application/Control No. 10/584,864	Applicant(s)/Patent Under Reexamination LEONE ET AL.	
		Examiner SHIN-HON CHEN	Art Unit 2431	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,690,930	02-2004	Dupre , Michael	455/411
*	B	US-5,534,857	07-1996	Laing et al.	340/5.74
*	C	US-2005/0021940	01-2005	Ma, Kenneth	713/155
*	D	US-7,177,425	02-2007	Ben-Chuan et al.	380/44
*	E	US-2005/0037752	02-2005	Kwan et al.	455/432.3
*	F	US-2004/0024846	02-2004	Randall et al.	709/219
*	G	US-6,504,932	01-2003	Vasnier et al.	380/273
*	H	US-2004/0204124	10-2004	Campbell, Lowell Lete	455/566
*	I	US-2004/0210766	10-2004	Kroselberg, Dirk	713/201
*	J	US-6,591,364	07-2003	Patel, Sarvar	713/170
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.